

旗舰型离子色谱





外束PIXE分析装置及其初步应用

鲁永芳 北京 北京师范大学低能核物理研究所 100875

王广甫 北京 北京师范大学分析测试中心 100875

摘 要:在GIC4117串列加速器上引出质子外束,引出窗口采用7 5μm厚Kapton膜。在外束管道前的RBS靶室中放置175nm金箔和金硅面垒探测器,可在外束PIXE分析的同时,用Au的RBS峰面积来监测束流积分。利用这一装置对古陶瓷和2幅书法作品进行分析。 关键词:

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The fecilities of external beam PIXE analysis and its preliminary applications

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Abstract: the facilities of external beam PIXE analysis have been set up at Tandetron Accalerator lab of Beijing Normal University. A 7.5 μ m thick Kapton film was used to seal the vacuum window. For measuring the number of incident proton, an Au(Si) surface barrier detector was employed to acquire the RBS spectrum of the 175 nm Au foil in the RBS chamber. Some porcelain and calligraphy spectra of extra beam PIXE acquired by the facilities were presented.

Key words:

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